PCN Number:			20180423001						PCN	l Da	ate:	Apr 25, 2018			
Title: Qualification		ation of	of GTBF as Additional Assembly/Test Site for Select Devices												
Cust	omer	Contac	et: E	PCN Manager		<u>er</u>		Dept:	Quality	/ Ser	vic	es			
Prop	osed	1 st Shi	Date:	e: Jul 25, 20			18	8 Estimated Availabilit				•			
Char	nge T	уре:		'											•
		bly Site					De	Design [Wafer Bump Site			
		nbly Prod					Da	Data Sheet				Wafer Bump Material			
		nbly Mat						Part number change				Wafer Bump Process			
		nical Sp						st Site			Щ	_		· Fab	
F	Packir	ng/Shipp	ing/Lab	eling	g		Te	st Process			<u>Ц</u>	Wafer Fab Materials			
												W	afer	· Fab	Process
							PC	N Detai	<u>ls</u>						
Desc	riptio	on of Ch	nange:												
and 7	Texas Instruments Incorporated is announcing the qualification GTBF as an Additional Assembly and Test Site for select devices listed in the "Product Affected" Section. Current assembly sites and Material differences are as follows.														
Ass	emb	ly Site	Asse	embly Site Origin			in	Assembly Country C			Co	ode Assembly Site City			
	NFM	IE			NFM			CHN				Chongchuan			
	GTE	BF .		(GTF			CHN			Dong Guan				
Mate	Material Differences:														
					NFME							G	TBF		
Mou	ınt Co	mpound						# A-09			SID# EY0000011				
Mole	d Com	pound			SID# R-17					SID# EN0000054					
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.															
Reason for Change:															
Continuity of Supply															
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):															
None															
Anticipated impact on Material Declaration															
Material Declaration			1	Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the II Eco-Info website . There is no impact to the material meeting current regulatory compliance requirements with this PCN change.											
Char	Changes to product identification resulting from this PCN:														

Assembly Site				
NFME	Assembly Site Origin (22L)	ASO: NFM		
GTBF (Great Team Backend Foundry)	Assembly Site Origin (22L)	ASO: GTF		

Sample product shipping label (not actual product label)





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812 (P) (2P) REV: (V) 0033317

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

TLV1117LV12DCYR	TLV1117LV15DCYT	TLV1117LV25DCYR	TLV1117LV30DCYT
TLV1117LV12DCYT	TLV1117LV18DCYR	TLV1117LV25DCYT	TLV1117LV33DCYR
TLV1117LV15DCYR	TLV1117LV18DCYT	TLV1117LV30DCYR	TLV1117LV33DCYT

Qualification Report

Qualify GTBF as Subcon A/T Site for PWR Packages: Phase 3 APP-LP-LDO Devices (4 pin SOT 223)

Approve Date 17-Apr-2018

Product Attributes

Attributes	Qual Device: TLV1117LV33DCYR		
Assembly Site	GTBF		
Package Family	SOT223		
Flammability Rating	UL 94 V-0		
Wafer Fab Supplier	MIHO8		
Wafer Process	LBC7		

⁻ Qual Device TLV1117LV33DCYR is qualified at LEVEL1-260CG

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TLV1117LV33DCYR
AC	Autoclave 121C	96 Hours	3/231/0
CDM	ESD - CDM	500 V	3/9/0
ED	Electrical Characterization	Per Datasheet Parameters	3/30/0
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0
HTOL	Life Test, 125C	336 Hours	3/231/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0
MSL	Moisture Sensitivity	Level 1-260C	3/36/0
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0
VM	Post Autoclave, Visual Quality Reliability Inspection	96 Hours	Pass
VM	Post Biased HAST, Visual Quality Reliability	96 Hours	Pass

	Inspection		
VIV	Post Temp. Cycle, Visual Quality Reliability Inspection	500 Cycles	Pass
YLI	FTY and Bin Summary		Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1000 Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1000 Hours, and 170C/420 Hours
- The following are equivalent Temperature Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page".

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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